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						Group Art Unit	4782· 2827
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TRANG	Sheet		1	of	2	Attorney Docket Number	4714P1/AMI-11

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Filing Late	10/3/2000
First Named Inventor	Ming Xi
Group Art Unit	1782 2823
Examiner Name	unassigned A ZARNERE
Attorney Docket Number	4714P1/AMI-11

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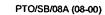
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First Named Inventor	Ming Xi								
Group Art Unit	Unassigned 1827								
Examiner Name	Unassigned ZAENEKE								
Attorney Docket Number	4714 PA /AMT-00-11								

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Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T2
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First Named Inventor	Ming Xi				
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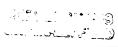
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